



## Features

- 3.3V Supply Voltage
- Crystal/CMOS Input: 25 MHz
- Four Differential Low-Power HCSL Outputs with On-Chip Termination
- Default ZOUT = 85Ω
- Two reference LVCMOS Outputs
- Programmable Slew Rate and Output Amplitude for Each Differential Output
- Selectable 0%, -0.3%, or -0.5% Spread on Differential Outputs
- Differential Output-to-Output Skew <50ps
- Very-Low phase Jitter for Differential Outputs  
< 0.3ps RMS, SSC off  
< 1.5ps RMS, SSC on
- LOS (Loss-Of-Signal) indication Clock input
- Totally Lead-Free & Fully RoHS Compliant
- Halogen and Antimony Free. “Green” Device
- Available in TQFN-32L package
- -40 to +85°C temperature operation

## Description

The RS2CG286 is a 4 differential LP-HCSL Outputs and 2 LVCMOS outputs, very-low-power PCIe Gen1/Gen2/Gen3/Gen4/Gen5 clock generator.

It uses a 25MHz crystal or CMOS reference as an input to generate the 100MHz low-power differential LP-HCSL outputs with on-chip terminations and the 25MHz LVCMOS buffered reference Single-ended outputs that are provided to serve as a low-noise reference for other circuitry.

It uses RSM's proprietary PLL design to achieve very-low jitter that meets PCIe Gen1~Gen5 requirements. It also provides various options, such as different slew rate and amplitude through SMBus, so users can easily configure the device to get the optimized performance. The device also supports selectable spread spectrum options to reduce EMI for various applications.

## Applications

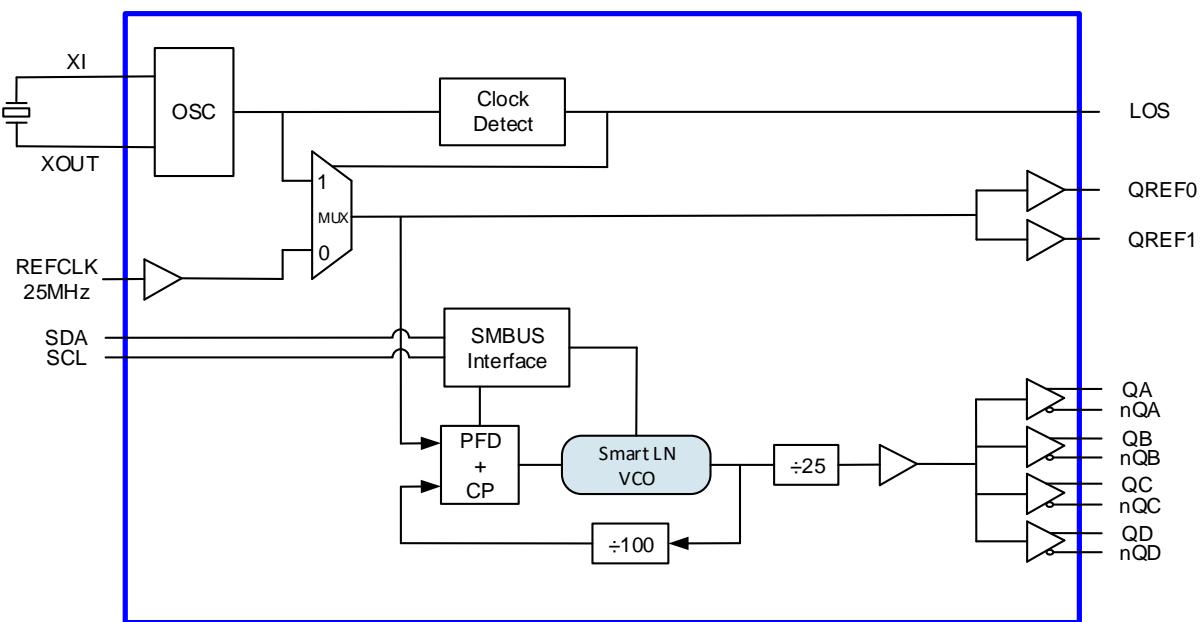
- Cloud/High-performance Computing
- nVME Storage
- In-Vehicle Networking
- Automotive infotainment

## Order information

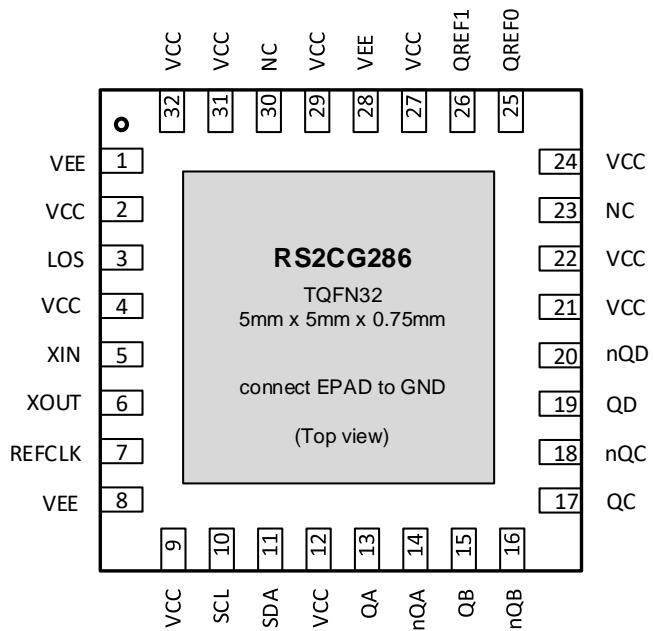
Part Number	Package	Description
RS2CG286ZHE	ZH	TQFN_32L_5mmx5mm



## Functional Block Diagram



## Pin Configuration





## Pin Descriptions

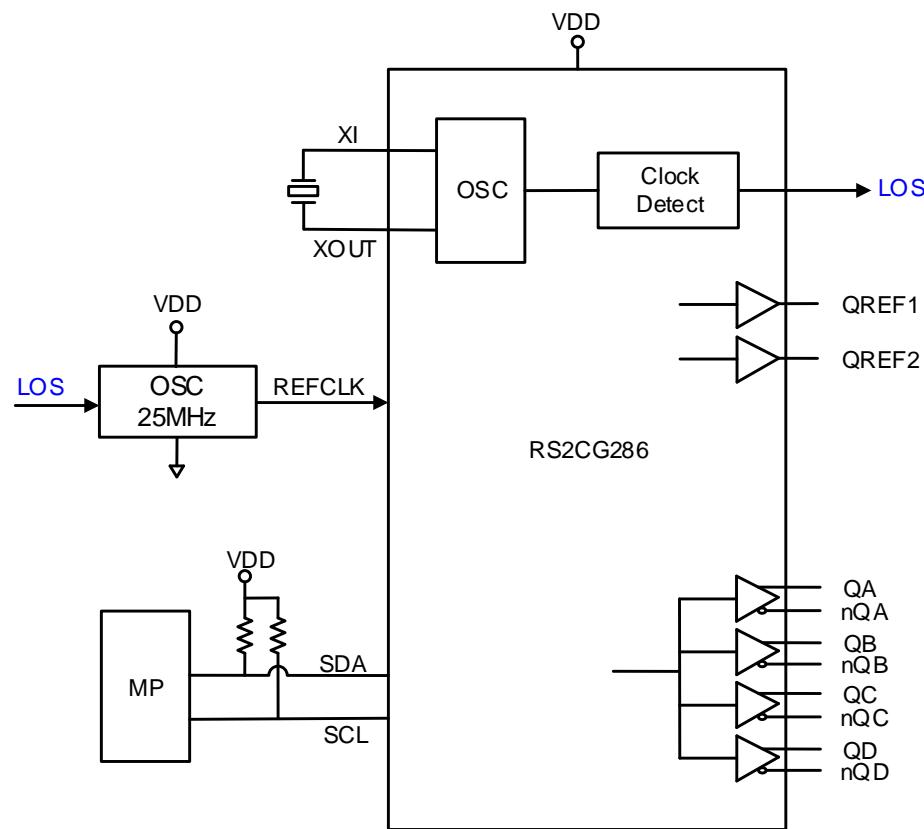
Pin Number	Name	Type	Description
1, 8, 28	VEE	Power	Negative supply pins (GND).
2,4,9, 12,21,22,24,27,29,31,32	VCC	Power	Pins 2, 24, 27 – Power supply for the 25MHz LVCMOS outputs Pin 4 –Power supply for the crystal oscillator Pin 9,12,21,22 –Power supply for the LP-HCSL differential outputs Pins 29 –Power supply for the divider Pin 31,32 –Power supply for the PLL
3	LOS	Output	Output indicating Loss of Input Signal. This pin is a TTL output. A high output on this pin indicates a loss of signal on XTAL input clock.
25,26	QREF0, QREF1	Output	Single-ended outputs. 3.3V LVCMOS/LVTTL reference levels.
5	XIN	Input	Parallel resonant crystal interface. XTAL_IN is the input.
6	XOUT	Output	Parallel resonant crystal interface. XTAL_OUT is the output,
7	REFCLK	Input	Single-ended LVCMOS/LVTTL reference clock input.
10,11	SCL, SDA	I/O	SMBus communication interface
23,30	NC	NC	No connect.
13,14	QA, nQA	Output	$\pm 0.8V$ Differential LP-HCSL interface levels
15,16	QB, nQB	Output	$\pm 0.8V$ Differential LP-HCSL interface levels
17,18	QC, nQC	Output	$\pm 0.8V$ Differential LP-HCSL interface levels
19,20	QD, nQD	Output	$\pm 0.8V$ Differential LP-HCSL interface levels

## Pin Characteristics

Symbol	Parameter		Test Conditions	MIN	TYP	MAX	Units
C <sub>IN</sub>	Input Capacitance		Crystal Not Included		2		pF
C <sub>PD</sub>	Power Dissipation Capacitance (per output)		QREF [0:1]	VCC = 3.6V		6	pF
R <sub>PU</sub>	Input Pullup Resistor				51		kΩ
R <sub>PD</sub>	Input Pulldown Resistor				51		kΩ
R <sub>OUT</sub>	Output Impedance		QREF [0:1]		33		Ω



## Typical Application Circuit



### Notes:

1. The LOS signal can be used to enable or disable the external OSC.



## Absolute Maximum Ratings

Symbol	Parameter	MIN	TYP	MAX	Unit
VDD	Supply Voltage to Ground Potential	-0.5	-	4.6	V
V <sub>IO</sub>	Input / Output Voltage	-0.5	-	VDD+0.5	V
V <sub>IH</sub>	SMBUS Input High Voltage			3.6	V
T <sub>J</sub>	Junction Temperature			125	°C
T <sub>store</sub>	Storage Temperature	-65	-	+150	°C
ESD	ESD HBM protection (input)			4000	V

Note: Stresses greater than those listed under MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

## Recommended Operating Conditions

Symbol	Parameter	MIN	TYP	MAX	Units
VDD	Power Supply Voltage	3.0		3.6	V
V <sub>IH</sub>	Input Voltage on REFCLK, SCL, SDA			3.6	V
T <sub>A</sub>	Ambient airtemperature	-40		+85	°C



## DC Electrical Characteristics

**Table 3. Power Supply DC Characteristics, VCC = 3.3V ± 0.3V, VEE = 0V, TA = -40°C to 85°C.**

Symbol	Parameter	Test Conditions	MIN	TYP	MAX	Units
VCC	Power Supply Voltage		3.0	3.3	3.6	V
ICC	Power Supply Current	No Load			200	mA

**Table 4. LVCMS DC Characteristics, VCC = 3.3V ± 0.3V, VEE = 0V, TA = -40°C to 85°C.**

Symbol	Parameter		Test Conditions	MIN	TYP	MAX	Units
IIH	Input High Current	REFCLK	VCC = VIN = 3.6V			150	µA
IIL	Input Low Current	REFCLK	VCC = 3.6V, VIN = 0V	-5			µA
VOH	Output High Voltage;		VCC = 3.3V ± 0.3V	2.3			V
VOL	Output Low Voltage;		VCC = 3.3V ± 0.3V			0.8	V

**Table 5. LP-HCSL DC Characteristics, VCC = 3.3V ± 0.3V, VEE = 0V, TA = -40°C to 85°C.**

Symbol	Parameter	Test Conditions	MIN	TYP	MAX	Units
VOH	Output High Voltage;		660		850	mV
VOL	Output Low Voltage;		-150		150	mV
Vomax	Output Maximum Voltage;			820	1150	mV
Vomin	Output Minimum Voltage;		-300	-42		mV
Voc	Output Cross Voltage;		250	380	550	mV

## Table 6. Crystal Characteristics

Parameter	Test Conditions	MIN	TYP	MAX	Units
Mode of Oscillation				Fundamental	
Frequency			25		MHz
Equivalent Series Resistance (ESR)				50	Ω
Shunt Capacitance				7	pF



## AC Electrical Characteristics

Table 7. LP-HCSL AC Characteristics, VCC = 3.3V ± 0.3V, VEE = 0V, TA = -40°C to 85°C.

Symbol	Parameter	Test Conditions	MIN	TYP	MAX	Units
f <sub>IN</sub>	Input Frequency			25		MHz
f <sub>OUT</sub>	Output Frequency	LP-HCSL		100		MHz
T <sub>jc-c</sub>	Cycle to cycle Jitter			20	60	ps
t <sub>sk(o)</sub>	Output Skew; NOTE 2, 3	Measured on the Rising Edge			50	ps
t <sub>R</sub> / t <sub>F</sub>	Slew rate	+/-150mV window		3		V/ns
ODC	Output Duty Cycle		45		55	%

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfm. The device will meet specifications after thermal equilibrium has been reached under these conditions

NOTE 1: Refer to the Phase Noise Plot.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at the differential crosspoints.

Table 8. AC Characteristics for Single Side Band Power Levels (LP-HCSL Outputs), VCC = 3.3V ± 0.3V, VEE = 0V, TA = 25°C.

Symbol	Parameter	Test Conditions	MIN	TYP	MAX	Units
t <sub>jPHASE</sub>	Integrated Phase Jitter (RMS)	PCIe Gen 1	-	25	86	ps
		PCIe Gen 2 Low Band, 10kHz < f < 1.5MHz	-	0.9	3.0	ps
		PCIe Gen 2 High Band, 1.5MHz < f < Nyquist (50MHz)	-	1.6	3.1	ps
		PCIe Gen3 Common Clock Architecture (PLL BW of 2-4 or 2-5MHz, CDR = 10MHz)	-	0.5	1	ps
		PCIe Gen3 Separate Reference No Spread (PLL BW of 2-4 or 2-5MHz, CDR=10 MHz)	-	0.5	0.7	ps
		PCIe Gen 4 (PLL BW of 2-4 or 2-5MHz, CDR = 10MHz)	-	0.37	0.5	ps
		PCIe Gen 5(7) (PLL BW of 500k to 1.8MHz. CDR = 20MHz)	-	0.05	0.15	ps
t <sub>jPH-SRISG2</sub>	Integrated Phase Jitter (RMS), -0.3%Spread	PCIe Gen 2, Separate Reference Independent Spread (PLL BW of 16MHz, CDR=5MHz)	-	0.92	2	ps
t <sub>jPH-SRISG3</sub>	Integrated Phase Jitter (RMS), -0.3% Spread	PCIe Gen 3, Separate Reference Independent Spread (PLL BW of 2-4MHz or 2-5MHz, CDR=10MHz)	-	0.4	0.7	ps
t <sub>jPH-SRISG2</sub>	Integrated Phase Jitter (RMS), -0.5% Spread	PCIe Gen 2, Separate Reference Independent Spread (PLL BW of 16MHz, CDR=5MHz)	-	1.1	2	ps
t <sub>jPH-SRISG3</sub>	Integrated Phase Jitter (RMS), -0.5% Spread	PCIe Gen 3, Separate Reference Independent Spread (PLL BW of 2-4MHz or 2-5MHz, CDR=10MHz)	-	0.6	0.7	ps



**Table 9. LVC MOS AC Characteristics, VCC = 3.3V ± 0.3V, VEE = 0V, TA = -40°C to 85°C.**

Symbol	Parameter		Test Conditions	MIN	TYP	MAX	Units
f <sub>IN</sub>	Input Frequency				25		MHz
f <sub>OUT</sub>	Output Frequency				25		MHz
t <sub>jit</sub>	RMS Phase Jitter (Random)		25MHz f <sub>OUT</sub> , 25MHz crystal Integration Range: 12kHz – 5MHz		0.140		ps
t <sub>sk(o)</sub>	Output Skew;	QREF [0:1]	Measured on the Rising Edge			50	ps
PSNR	Power Supply Noise Reduction	Pin 40, (VCC)	From DC to 6.25MHz		-80		dB
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time		20% to 80%		1.0	1.5	ns
ODC	Output Duty Cycle			45		55	%

**Table 10. AC Characteristics for Single Side Band Power Levels (LVC MOS Outputs), VCC = 3.3V ± 0.3V, VEE = 0V, TA = 25°C.**

Symbol	Parameter	Test Conditions	MIN	TYP	MAX	Units
φN(1k)	Single-side band phase noise, 1kHz from Carrier	25MHz		-137		dBc/Hz
φN(10k)	Single-side band phase noise, 10kHz from Carrier			-153		dBc/Hz
φ(100k)	Single-side band phase noise, 100kHz from Carrier			-162		dBc/Hz
φN(1M)	Single-side band phase noise, 1MHz from Carrier			-163		dBc/Hz
φN(5M)	Single-side band phase noise, 5MHz from Carrier			-163		dBc/Hz



## SMBus Serial Data Interface

RS2CG286 is a slave only device that supports block read and block write protocol using a single 7-bit address and read/write bit as shown below. Read and write block transfers can be stopped after any complete byte transfer.

**Table 11. Address Assignment**

A6	A5	A4	A3	A2	A1	A0	R/W
1	1	0	1	0	0	0	0/1

**Table 12. How to Write**

1 bit	7 bit	1 bit	1 bit	8 bit	1 bit	8 bit	1 bit	8 bit	1 bit		8 bit	1 bit	1 bit
Start bit	Add.	W(0)	Ack	Beginning Byte location = N	Ack	Data Byte count=X	Ack	Beginning Data Byte (N)	Ack	.....	Data Byte (N+X-1)	Ack	Stop bit

**Table 13. How to Read**

1 bit	7 bit	1 bit	1 bit	8 bit	1 bit	1 bit	7 bit	1 bit	1 bit	8 bit	1 bit	8 bit	1 bit
Start bit	Add.	W(0)	Ack	Beginning Byte location = N	Ack	Repeat Start bit	Add.	R(1)	Ack	Data Byte count = X	Ack	Beginning Data Byte (N)	Ack

										8 bit	1 bit	1 bit	
.....										Data Byte (N+X-1)	NAck	Stop bit	



**Table 14. Output Enable Control 0**

Byte 0	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			1
Bit 6	Reserved		RW			1
Bit 5	Reserved		RW			1
Bit 4	Reserved		RW			1
Bit 3	OE_OUTA		RW	Disable Output	Enable Output	1
Bit 2	OE_OUTB		RW	Disable Output	Enable Output	1
Bit 1	OE_OUTC		RW	Disable Output	Enable Output	1
Bit 0	OE_OUTD		RW	Disable Output	Enable Output	1

**Table 15. Output status Control 1**

Byte 1	Name	Control Function	Type	0	1	Default
Bit 7	SLEW RATE OF HCSL	HCSL SLEW RATE CONTROL	RW	Slow setting	Fast setting	0
Bit 6	STOP1	HCSL Stop Mode Control	RW	00= Low / Low 01= HIZ / HIZ 10= High / Low 11= Low / High		0
Bit 5	STOP0					0
Bit 4	HCSL PD	HCSL PD MODE	RW	Normal	PD	0
Bit 3	Reserved					0
Bit 2	Reserved					0
Bit 1	Reserved					0
Bit 0	REF HIZ	Output REF CMOS HIZ MODE	RW	0=Normal	1=REF HIZ	0

**Table 16. Reserved**

Byte 2	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0

**Table 17. Reserved**

Byte 3	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0



**Table 18. Reserved**

Byte 4	Name	Type	0	1	Default
Bit 7	Reserved	RW			0
Bit 6	Reserved	RW			0
Bit 5	Reserved	RW			0
Bit 4	Reserved	RW			0
Bit 3	Reserved	RW			0
Bit 2	Reserved	RW			0
Bit 1	Reserved	RW			0
Bit 0	Reserved	RW			0

**Table 19. Reserved**

Byte 5	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0

**Table 20. Reserved**

Byte 6	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0

**Table 21. Reserved**

Byte 7	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0



**Table 22. Vendor/Revision Identification Control**

Byte 8	Name	Control Function	Type	0	1	Default
Bit 7	RID3	Revision ID	R	Rev A = 0000		0
Bit 6	RID2		R			0
Bit 5	RID1		R			0
Bit 4	RID0		R			0
Bit 3	VID3	Vendor ID	R	RSM = 0011		0
Bit 2	VID2		R			0
Bit 1	VID1		R			1
Bit 0	VID0		R			1

**Table 23. Device ID Control**

Byte 9	Name	Control Function	Type	0	1	Default
Bit 7	DID7	Device ID	R			0
Bit 6	DID6		R			0
Bit 5	DID5		R			0
Bit 4	DID4		R			0
Bit 3	DID3		R			0
Bit 2	DID2		R			1
Bit 1	DID1		R			1
Bit 0	DID0		R			1

**Table 24. Byte Count Control**

Byte 10	Name	Control Function	Type	0	1	Default
Bit 7	Reserved	Writing to this register configures how many bytes will be read back	RW			0
Bit 6	Reserved		RW			0
Bit 5	BC5		RW	Default value is 8		0
Bit 4	BC4		RW			0
Bit 3	BC3		RW			1
Bit 2	BC2		RW			0
Bit 1	BC1		RW			0
Bit 0	BC0		RW			0

**Table 25. Reserved**

Byte 11	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0



**Table 26. Reserved**

Byte 12	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0

**Table 27. Reserved**

Byte 13	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0

**Table 28. Reserved**

Byte 14	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0

**Table 29. Reserved**

Byte 15	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0



**Table 30. Reserved**

Byte 16	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0

**Table 31. Reserved**

Byte 17	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0

**Table 32. Reserved**

Byte 18	Name	Control Function	Type	0	1	Default
Bit 7	Reserved	Write not allowed	RW			0
Bit 6	Reserved	Write not allowed	RW			1
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0

**Table 33. Reserved**

Byte 19	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	Reserved		RW			0
Bit 5	Reserved		RW			0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved		RW			0
Bit 0	Reserved		RW			0



**Table 34. SSC Control**

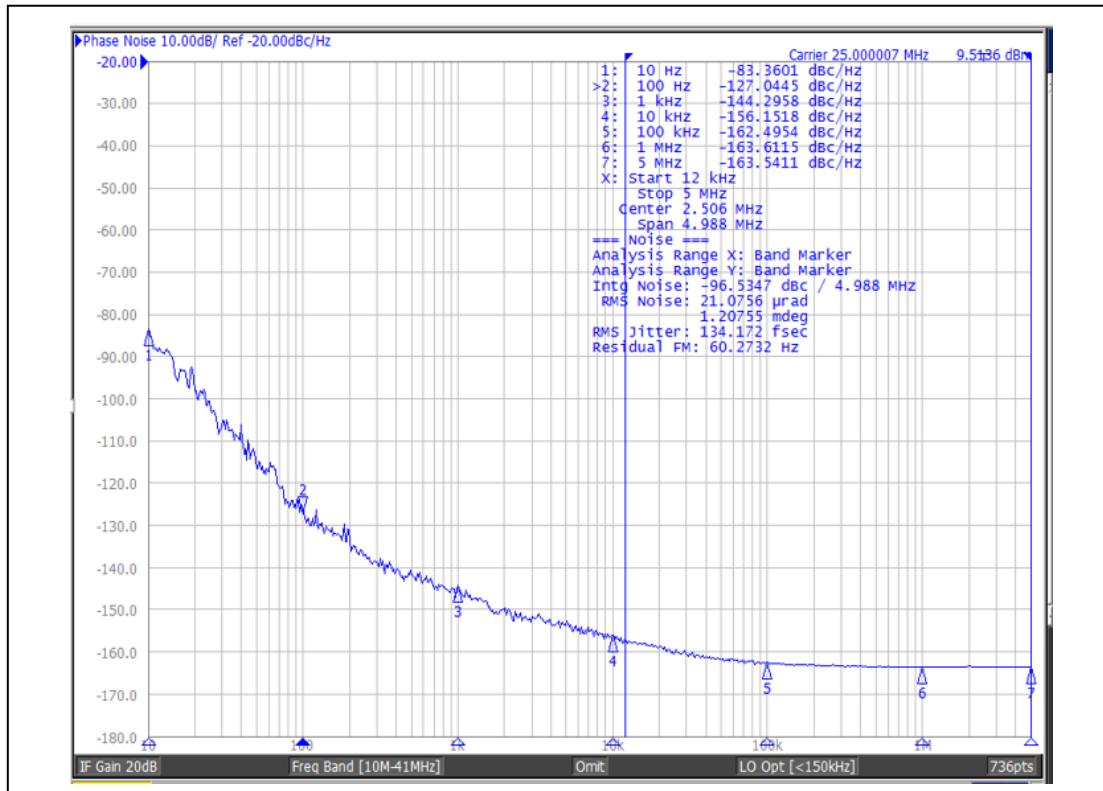
Byte 20	Name	Control Function	Type	0	1	Default
Bit 7	Reserved		RW			0
Bit 6	SSC_DIV6	SSC clk divider ratio = N*2+1 $F_{SSC} = F_{PFD\_FB} / (N*2+1) / 12$ B20[1] is RO/RW when B20[7]=0/1	RW	Divide ratio = decimal value x 2 + 1		
Bit 5	SSC_DIV5		RW	0		
Bit 4	SSC_DIV4		RW	0		
Bit 3	Reserved		RW	0		
Bit 2	Reserved		RW	0		
Bit 1	Reserved		RW	0		
Bit 0	Reserved		RW	0		

**Table 35. SSC and EFUSE Control**

Byte 21	Name	Control Function	Type	0	1	Default
Bit 7	SSC_PD	SSC block power down valid if CG is SSC mode	RW	Normal	Power down	0
Bit 6	SSC_EN_SW1	SSC_EN SW control	RW	00 = SSC off 01 = -0.3% SS 10 = -0.3% SS 11 = -0.5% SS		0
Bit 5	SSC_EN_SW0					0
Bit 4	Reserved		RW			0
Bit 3	Reserved		RW			0
Bit 2	Reserved		RW			0
Bit 1	Reserved	Write not allowed	RW	00 = ACCESS0 / ACCESS0 01 = RE / PEB 10 = OUTPUT1 / ACCESS1 11 = OUTPUT0 / ADDR0		0
Bit 0	Reserved					0



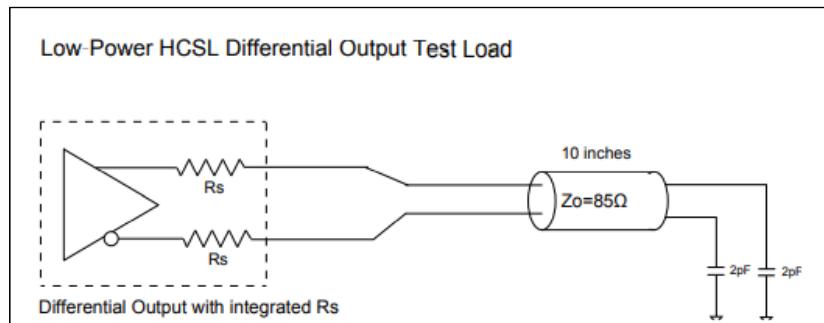
### Plots 25MHz LVCMOS Clock (12k to 5MHz)



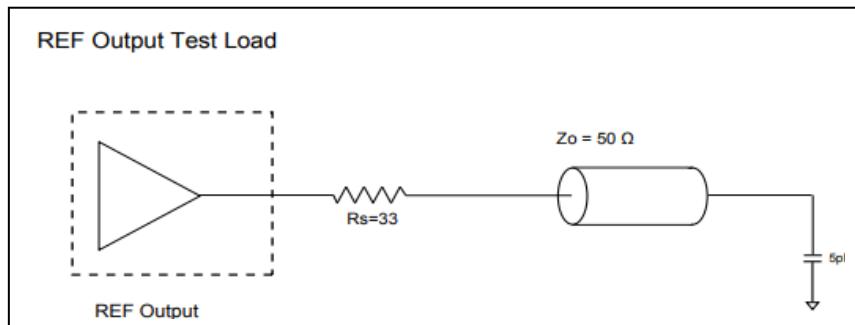


## Typical Test Circuit

### Low-Power HCSL Test Circuit



### CMOS REF Test Circuit



### Differential Output Driving LVDS

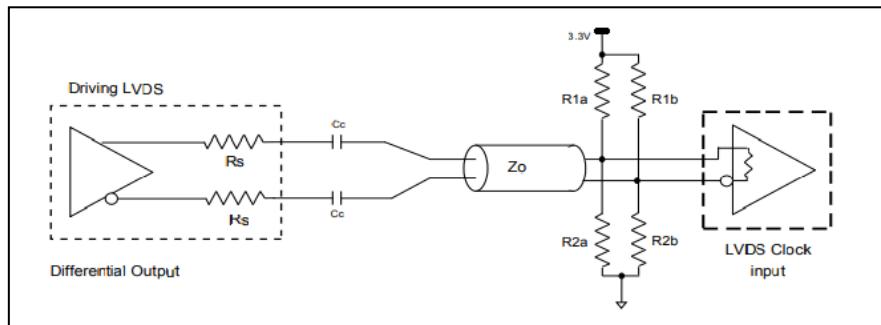


Table 36. Alternate Differential Output Terminations ( $Z_o = 85\Omega$ ).

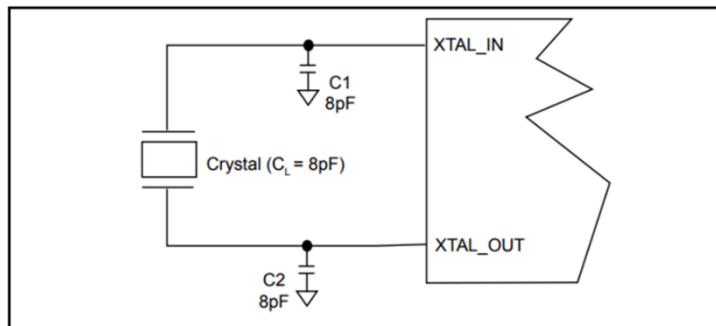
Component	Receiver with Termination	Receiver without Termination	Unit
R1a, R1b	10,000	130	Ω
R2a, R2b	5600	64	Ω
Cc	0.1	0.1	μF
V <sub>CM</sub>	1.2	1.2	V



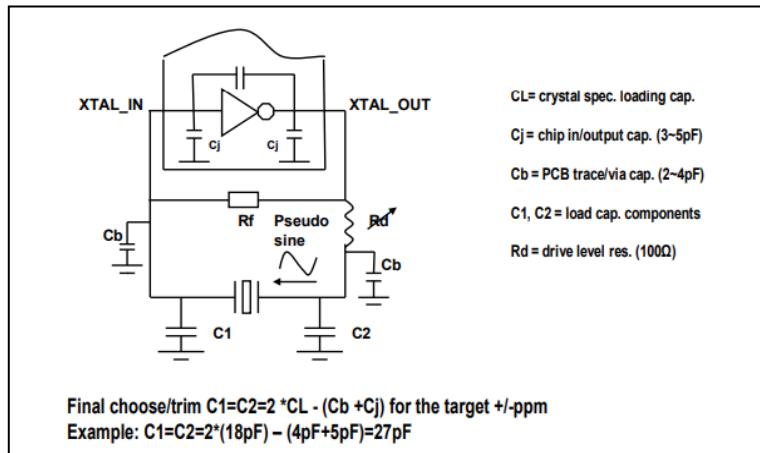
## Crystal Circuit Connection

The following diagram shows RS2CG286 crystal circuit connection with a parallel crystal. For the  $C_L=8\text{pF}$  crystal, it is suggested to use  $C_1=8\text{pF}$  and  $C_2=8\text{pF}$ .  $C_1$  and  $C_2$  can be adjusted to fine tune to the target ppm of crystal oscillator according to different board layouts based on the following formular in the Crystal Capacitor Calculation diagram.

### Crystal Oscillator Circuit



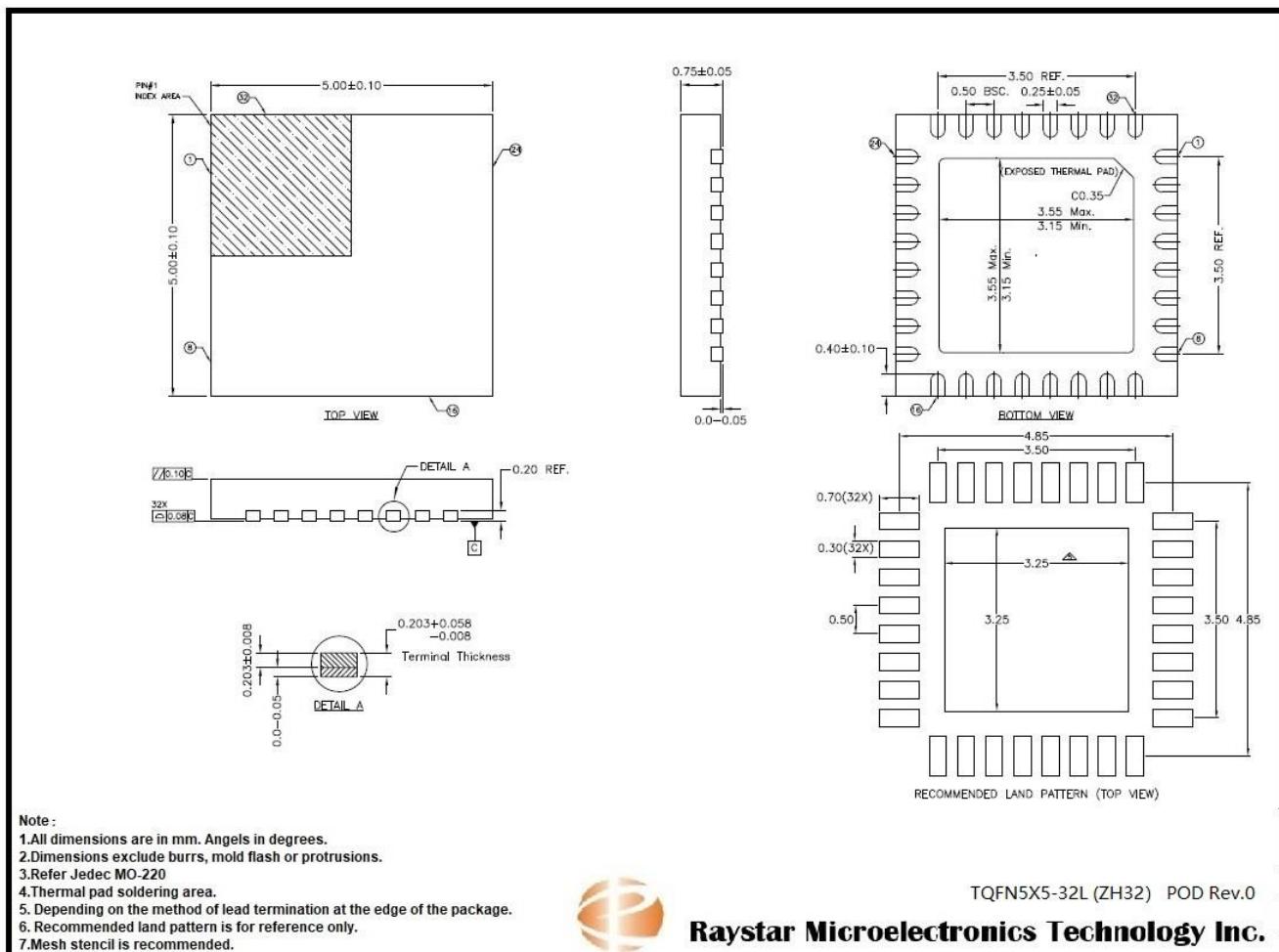
### Crystal Capacitor Calculation





## Package Information

### TQFN-32L (ZH32)





## Revision History

Revision	Description	Date
0.9	1.Preliminary.	2023/9/16
1.0	1.Official Release.	2024/1/30
1.1	1.Update Pin Configuration. 2.Update the Plots. 3.Update the LP_HCSL Test Circuit and Oscillator Circuit.	2024/7/19
1.2	1. Modify the operation temperature range to -40~85°C 2. Modify the document No. to RSM-DS-R-0116	2024/9/18